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标题: Terahertz phase microscopy in the sub-wavelength regime
作者: Yi, M (Yi, Minwoo); Lee, K (Lee, Kanghee); Song, JD (Song, Jin-Dong); Ahn, J (Ahn, Jaewook)
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摘要: Gouy phase shift is a well-known behavior that occurs when a propagating light is focused, but its behavior in the sub-wavelength confinement is not yet known. Here, we report the theoretical and experimental study of the aperture-size dependency of the Gouy phase shift in the sub-wavelength diffraction regime. In experiments carried out with laser-induced terahertz (THz) wave emission from various semiconductor apertures, we demonstrate the use of Guoy phase shit for sub-wavelength THz microscopy. (C) 2012 American Institute of Physics. [http://dx.doi.org/10.1063/1.4705294]
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地址: [Yi, Minwoo; Lee, Kanghee; Ahn, Jaewook] Korea Adv Inst Sci & Technol, Dept Phys, Taejon 305701, South Korea
[Song, Jin-Dong] Korea Inst Sci & Technol, Nano Photon Res Ctr, Seoul 136791, South Korea
通讯作者地址: Yi, M (通讯作者),Korea Adv Inst Sci & Technol, Dept Phys, Taejon 305701, South Korea
电子邮件地址: jwahn@kaist.ac.kr
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